

December 2010

# FDB016N04AL7

# N-Channel PowerTrench® MOSFET **40V**, **306A**, **1.6m** $\Omega$

### **Features**

- $R_{DS(on)} = 1.16m\Omega$  (Typ.)@  $V_{GS} = 10V$ ,  $I_D = 80A$
- · Fast Switching Speed
- · Low Gate Charge
- · High Performance Trench Technology for Extremely Low
- · High Power and Current Handling Capability
- · RoHS Compliant

# **Description**

This N-Channel MOSFET is produced using Fairchild Semiconductor's adcanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

# **Application**

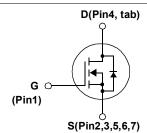
• DC to DC Convertors / Synchronous Rectification







D<sup>2</sup>-PAK-7L FDB Series with suffix - L7



## MOSFET Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter	FDB016N04AL7	Units
V <sub>DSS</sub>	Drain to Source Voltage		40	V
$V_{GSS}$	Gate to Source Voltage	±20	V	
		- Continuous (T <sub>C</sub> = 25°C, Silicon Limited)	306*	
l <sub>D</sub>	Drain Current	- Continuous (T <sub>C</sub> = 100°C, Silicon Limited)	216*	Α
	- Continuous (T <sub>C</sub> = 25°C, Package Limited)	160		
DM	Drain Current	- Pulsed (Note 1)	1224	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		1350	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)		6.0	V/ns
3	Dawer Dissination	$(T_C = 25^{\circ}C)$	283	W
P <sub>D</sub> Power Dissipation	Power Dissipation	- Derate above 25°C	1.89	W/°C
Γ <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Te	mperature Range	-55 to +175	οС
Γ <sub>L</sub>	Maximum Lead Temperat 1/8" from Case for 5 Seco	Maximum Lead Temperature for Soldering Purpose,		°C

<sup>\*</sup>Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 160A.

#### Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.53	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	· C/VV

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB016N04A	FDB016N04AL7	D2-PAK-7L	330mm	24mm	800

# Electrical Characteristics T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	eteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0V$ , $T_C = 25^{\circ}C$	40	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	-	0.03	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 32V, V <sub>GS</sub> = 0V	-	-	10	
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{DS} = 32V, T_C = 150^{\circ}C$	-	-	500	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	V <sub>GS</sub> = ±20V, V <sub>DS</sub> = 0V	-	-	±100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.0	-	3.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 80A	-	1.16	1.6	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 10V, I <sub>D</sub> = 80A (Note 4)	-	381	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	)/ OF)/ )/ O)/		-	8715	11600	pF
Coss	Output Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V f = 1MHz		-	2035	2710	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1141112		-	230	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V			-	129	167	nC
$Q_{gs}$	Gate to Source Gate Charge V <sub>DS</sub> = 32V, I <sub>D</sub> = 80A		-	28	-	nC	
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	V <sub>GS</sub> = 10V		-	12	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		(Note 4, 5)	-	17	-	nC

# **Switching Characteristics**

$t_{d(on)}$	Turn-On Delay Time		-	21	52	ns
t <sub>r</sub>		$V_{DD} = 20V, I_D = 80A$	-	14	38	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{GEN}$ = 4.7 $\Omega$ , $V_{GS}$ = 10 $V$	-	118	246	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)	-	33	76	ns
ESR	Equivalent Series Resistance (G-S)		-	1.25	-	Ω

### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	306	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	1224	Α
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 80A$	-	-	1.3	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>SD</sub> = 80A	-	68	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$ (Note	4) -	84	-	nC

#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 3mH, I $_{AS}$  = 30A, V $_{DD}$  = 25V, R $_{G}$  = 25 $\Omega$ , Starting T $_{J}$  = 25°C
- 3. I  $_{SD}$   $\leq$  80A, di/dt  $\leq$  200A/ $\mu$ s,  $V_{DD}$   $\leq$  BV $_{DSS}$ , Starting T $_{J}$  = 25°C
- 4. Pulse Test: Pulse width  $\leq 300 \mu s, \, Duty \, Cycle \leq 2\%$
- 5. Essentially Independent of Operating Temperature Typical Characteristics

FDB016N04AL7 Rev. A1 2 www.fairchildsemi.com

# **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

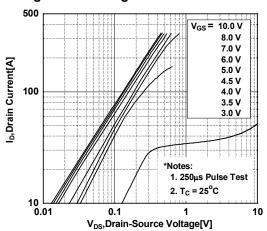


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

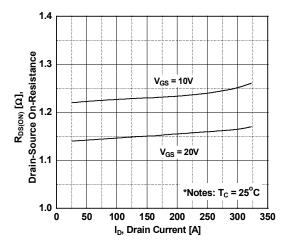


Figure 5. Capacitance Characteristics

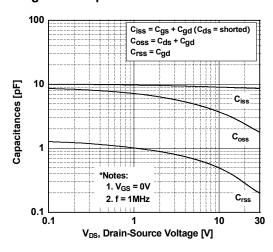


Figure 2. Transfer Characteristics

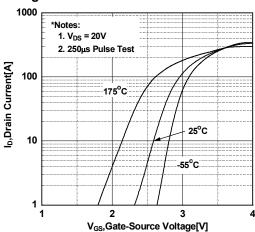


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

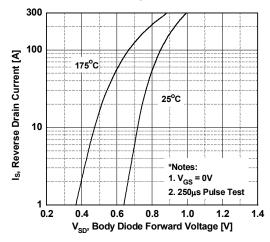
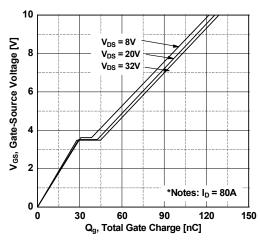


Figure 6. Gate Charge Characteristics



FDB016N04AL7 Rev. A1 3 www.fairchildsemi.com

# **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

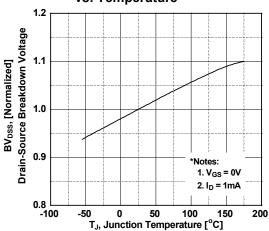


Figure 9. Maximum Safe Operating Area

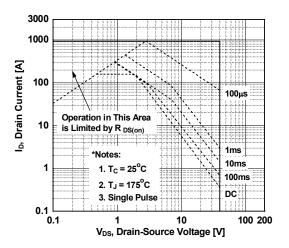


Figure 11. Unclamped Inductive Switching Capability

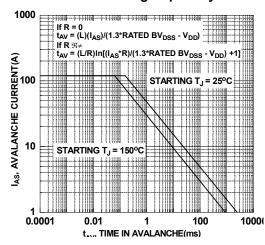


Figure 8. On-Resistance Variation vs. Temperature

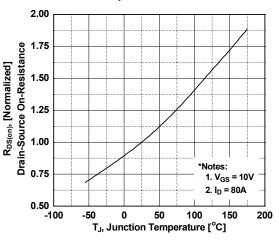
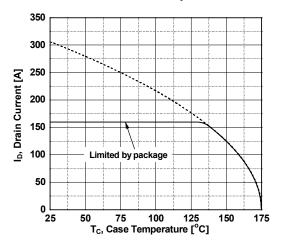


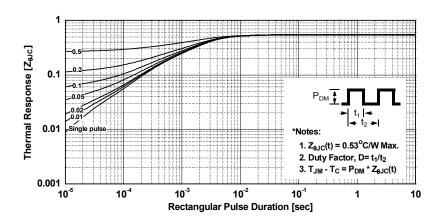
Figure 10. Maximum Drain Current vs.

Case Temperature

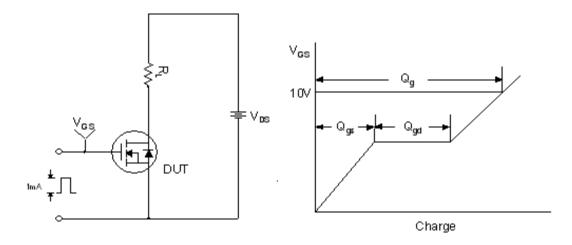


FDB016N04AL7 Rev. A1 4 www.fairchildsemi.com

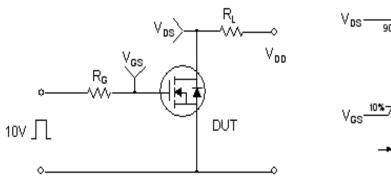


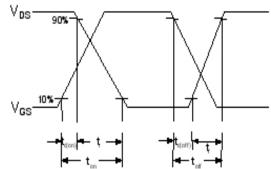


## **Gate Charge Test Circuit & Waveform**

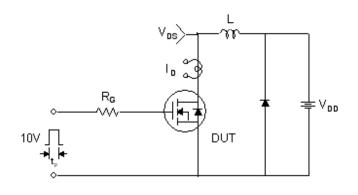


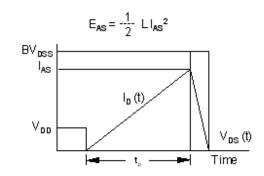
### **Resistive Switching Test Circuit & Waveforms**



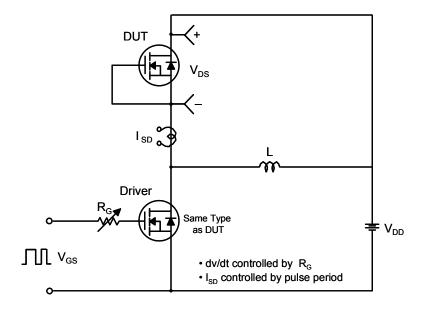


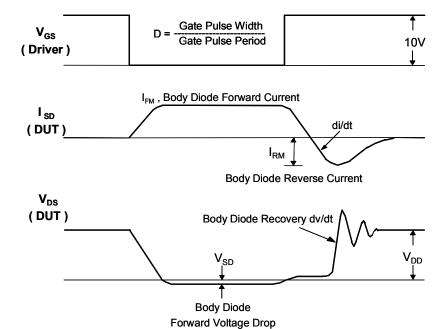
## **Unclamped Inductive Switching Test Circuit & Waveforms**

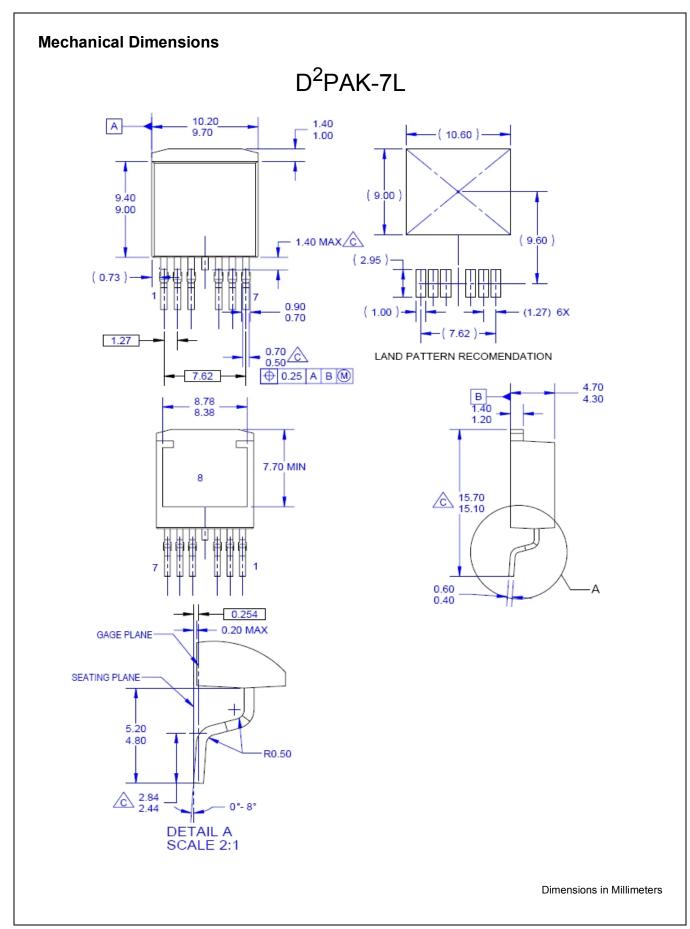




### Peak Diode Recovery dv/dt Test Circuit & Waveforms











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Rev. I51